

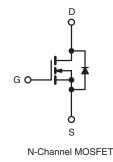
## F630FI-VB Datasheet N-Channel 200 V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	200					
R <sub>DS(on)</sub> (Ω)	$V_{GS} = 10 V$	0.265				
Q <sub>g</sub> (Max.) (nC)	16					
Q <sub>gs</sub> (nC)	5					
Q <sub>gd</sub> (nC)	8					
Configuration	Single					

#### **FEATURES**

- Isolated Package
- High Voltage Isolation = 2.5 kV<sub>RMS</sub> (t = 60 s; f = 60 Hz)
- Sink to Lead Creepage Distance = 4.8 mm
- 175 °C Operating Temperature
- · Dynamic dV/dt Rating
- Low Thermal Resistance
- Lead (Pb)-free Available





<b>ABSOLUTE MAXIMUM RATINGS</b> T	<sub>C</sub> = 25 °C, u	nless otherw	ise noted			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	200	- V	
Gate-Source Voltage			V <sub>GS</sub>	± 20		
Continuous Drain Current	V <sub>GS</sub> at 10 V	$T_{C} = 25 \degree C$ $T_{C} = 100 \degree C$	- I <sub>D</sub>	10		
	VGS at 10 V	T <sub>C</sub> = 100 °C		6.5	A	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	32		
Linear Derating Factor				0.24	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	36	mJ	
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	7.2	A	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	3.7	mJ	
Maximum Power Dissipation	issipation T <sub>C</sub> = 25 °C		PD	37	W	
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	5.5	V/ns	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	°C		
Soldering Recommendations (Peak Temperature)	for	10 s		300 <sup>d</sup>		
Mounting Torque	6-32 or I	6-32 or M3 screw		10	lbf ⋅ in	
	0-02 OF IND SCIEW			1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b.  $V_{DD} = 25 \text{ V}$ , starting  $T_J = 25 \text{ °C}$ , L = 1.0 mH,  $R_G = 25 \Omega$ ,  $I_{AS} = 7.2 \text{ A}$  (see fig. 12). c.  $I_{SD} \le 9.2 \text{ A}$ , dl/dt  $\le 110 \text{ A/}\mu\text{s}$ ,  $V_{DD} \le V_{DS}$ ,  $T_J \le 175 \text{ °C}$ .

d. 1.6 mm from case.





PARAMETER	SYMBOL	TYP. MAX.			UNIT			
Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 65 - 4.1			- °C/W			
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>							
SPECIFICATIONS $T_J=25\ ^\circ C,\ \tau$	unless other	vise noted						
PARAMETER	SYMBOL	TES	ST CONDITIO	NS	MIN.	TYP.	MAX.	UNI
Static								
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$			200	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference	ce to 25 °C, I <sub>D</sub>	= 1 mA	-	0.13	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250	Ο μΑ	2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ± 20 V			-	-	± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =	V <sub>DS</sub> = 200 V, V <sub>GS</sub> = 0 V			-	25	
		V <sub>DS</sub> =160 V	, V <sub>GS</sub> = 0 V, T	J = 150 °C	-	-	250	μΑ
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> =	4.3 A <sup>b</sup>	-	0.265	-	Ω
Forward Transconductance	<b>g</b> <sub>fs</sub>	V <sub>DS</sub> =	= 50 V, I <sub>D</sub> = 4.	3 A <sup>b</sup>	2.3	-	-	S
Dynamic								•
Input Capacitance	C <sub>iss</sub>	$V_{cc} = 0 V_{cc}$			-	560	-	pF
Output Capacitance	Coss	$V_{GS} = 0 V, V_{DS} = 25 V, f = 1.0 MHz, see fig. 5 f = 1.0 MHz$		-	260	-		
Reverse Transfer Capacitance	C <sub>rss</sub>			-	110	-		
Drain to Sink Capacitance	С				-	12	-	
Total Gate Charge	Qg			-	-	16		
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V		9.2 A, V <sub>DS</sub> = 80 V, ee fig. 6 and 13 <sup>b</sup>	-	-	4.4	nC
Gate-Drain Charge	Q <sub>gd</sub>	-	see lig. 6 and 13°		-	-	7.7	1
Turn-On Delay Time	t <sub>d(on)</sub>				-	8.8	-	-
Rise Time	t <sub>r</sub>		$V_{DD} = 100 \text{ V}, \text{ I}_{D} = 9.2 \text{ A},$		-	30	-	
Turn-Off Delay Time	t <sub>d(off)</sub>	$R_{G} = 18 \ \Omega, R_{D} = 5.2 \ \Omega,$ see fig. 10 <sup>b</sup>		-	19	-	ns	
Fall Time	t <sub>f</sub>			-	20	-		
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH	
Internal Source Inductance	L <sub>S</sub>			-	7.5	-		
Drain-Source Body Diode Characteristic	s							
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	10	-	A	
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	32	-		
Body Diode Voltage	$V_{SD}$	T <sub>J</sub> = 25 °C	$T_J = 25 \ ^{\circ}C, \ I_S = 7.2 \ A, \ V_{GS} = 0 \ V^b$		-	-	2.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \ ^{\circ}C, I_F = 9.2 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	130	260	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	0.65	1.3	μC	
Forward Turn-On Time	t <sub>on</sub>	Intrinsic tu	urn-on time is	negligible (turn	-on is dor	ninated by	Ls and I	_n)

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width  $\leq$  300  $\mu s;$  duty cycle  $\leq$  2 %.



#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

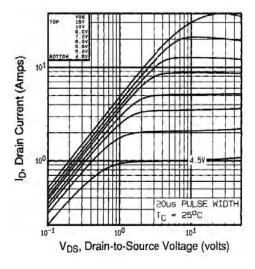


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

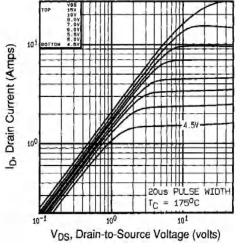


Fig. 2 - Typical Output Characteristics,  $T_C$  = 175  $^\circ C$ 

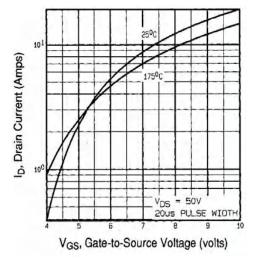


Fig. 3 - Typical Transfer Characteristics

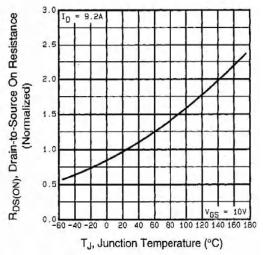


Fig. 4 - Normalized On-Resistance vs. Temperature



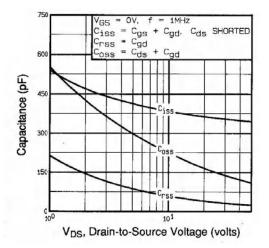


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

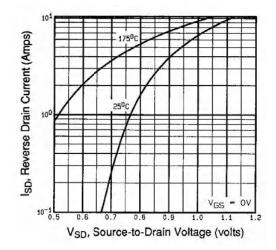


Fig. 7 - Typical Source-Drain Diode Forward Voltage

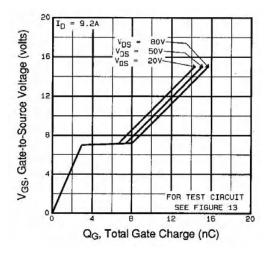


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

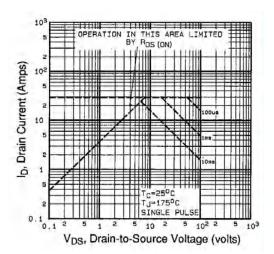


Fig. 5 - Fig. 8 - Maximum Safe Operating Area



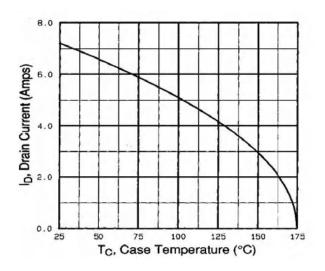


Fig. 9 - Maximum Drain Current vs. Case Temperature

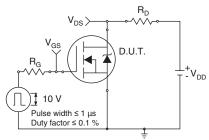


Fig. 10a - Switching Time Test Circuit

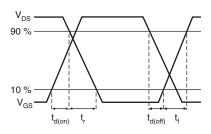
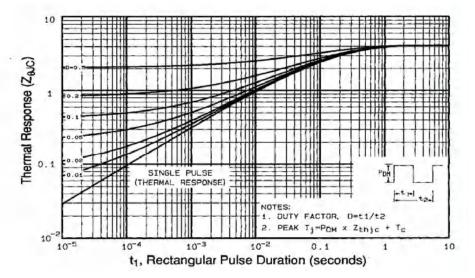
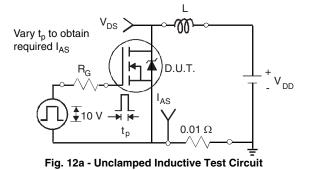


Fig. 10b - Switching Time Waveforms







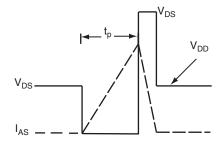
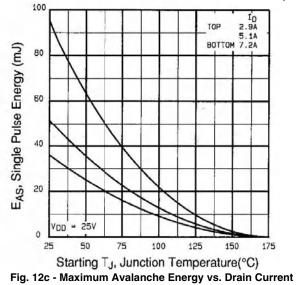
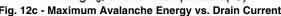


Fig. 12b - Unclamped Inductive Waveforms







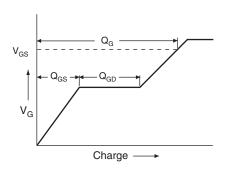
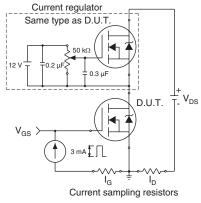
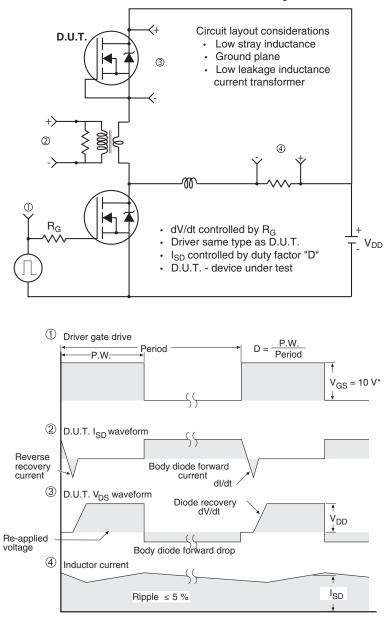


Fig. 13a - Basic Gate Charge Waveform









### Peak Diode Recovery dV/dt Test Circuit

\*  $V_{GS} = 5 V$  for logic level devices

Fig. 14 - For N-Channel



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